LHX-302-COC Laser Reliability and aging test system

Using the LHX-302-COC semiconductor laser life and aging test system can reduce test costs and increase test efficiency. The system contains 40 aging drawers that can be independently heated and loaded to support up to 1280 devices. You can conduct multiple independent tests at the same time to increase production and reduce costs.

The design of LHX-302-COC is very flexible, allowing you to test a variety of different package formats in one system, simply by replacing different aging drawers. The system supports ACC and LIV tests. The typical current is 200mA per channel and can be customized up to 2000mA output.

Reliability Sys software can help you to make testing more efficient. You can easily configure a variety of types of devices and test methods. The software automatically analyzes, saves, and exports test results, provides a variety of error mode processing. It does not require any additional programming by the user, even if the power is down, it will not affect the integrity of the data. Data can also be imported into a csv file and analyzed by other software.

- High density, up to 1280 lasers can be aged at the same time
- Temperature control from 40°C to 120°C
- Current output in drawer units
- Support TO, butterfly, COC and custom package
Supports probe spacing down to 300μm
Current range up to 2000mA
Current mode: ACC, APC (custom), LIV
Hot swap, easy operation, safe and reliable data management
Modularized design, easy to expand

Current’s long-term stability: 0.2%

Based on our years of precision control and testing technology for semiconductor lasers, LHX-302-COC provides you with a long-term, stable aging and life cycle testing system to help you to get accurate test results with good repeatability.

Temperature control’s long-term stability: ± 1 degree

The system integrates a high-stability temperature control module with long-term temperature stability (> 48 hours) ± 1 degree.

32 devices per drawer for high test reliability

To help our users to get ahead in the high-speed communication laser market, we pay special attention to materials selection and mechanical fixture design to help users to get high-reliability aging systems at a lower cost.

Multi-channel synchronous test to meet the need for flexibility in R&D activities

The LIV-302 test system used with the aging system can perform LIV scan on 32 devices in the drawer at the same time to obtain accurate test data. The repeatability of the threshold calculation can be less than 3%.
LHX-3100-80 Laser life cycle and aging test system

- High density, low cost
- From 40°C to 180°C, multi-channel synchronous temperature control
- Supports TO and butterfly packages
- Current range up to 200mA
- Current mode: ACC
- Modularized design, easy to expand, each layer can support 80 devices at the same time
- Concise software design, safe and reliable data management
- High temperature cabinet can be configured by users
LHX-3102 High power Laser life cycle and aging test system

- 4 channels output per layer, up to 10 layers
- High power, current range up to 15A20V
- Temperature range from 20°C to 65°C
- Water cooling combined with TEC cooling, high stability in long-term temperature control
- Independently control current in each channel current and parallel current output
- Fixtures can be customized for multiple lasers working in single channel
- Support TO, COS, C Mount and custom package
- Current mode: ACC, APC (custom), LIV (custom)
- Modularized design, easy to expand
- Concise software design, safe and reliable data management
### Current Specifications

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Specification</th>
</tr>
</thead>
<tbody>
<tr>
<td>LD current setting range</td>
<td>0~15A</td>
</tr>
<tr>
<td>LD current setting accuracy</td>
<td>±1% * F.S.</td>
</tr>
<tr>
<td>LD Current limit setting range</td>
<td>0~15.15A</td>
</tr>
<tr>
<td>LD compliance voltage</td>
<td>5V (typ), up to 20V</td>
</tr>
</tbody>
</table>

### Measurement Specifications

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Specification</th>
</tr>
</thead>
<tbody>
<tr>
<td>Current measurement range</td>
<td>0~15A</td>
</tr>
<tr>
<td>Current measurement accuracy</td>
<td>±1% * F.S.</td>
</tr>
<tr>
<td>Voltage measurement range</td>
<td>0~5V (typ), up to 20V</td>
</tr>
<tr>
<td>Voltage measurement accuracy</td>
<td>±1% * F.S.</td>
</tr>
</tbody>
</table>

### General Specification

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Specification</th>
</tr>
</thead>
<tbody>
<tr>
<td>Work voltage</td>
<td>AC200-240V, 50/60Hz, 400W/layer</td>
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<tr>
<td>Current output interface</td>
<td>D-sub, 9w4</td>
</tr>
<tr>
<td>Communication Interface</td>
<td>Ethernet</td>
</tr>
</tbody>
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![CMount Fixture](image1.png)  
![CMount LD](image2.png)  
![CMount LD](image3.png)  
![COS LD](image4.png)